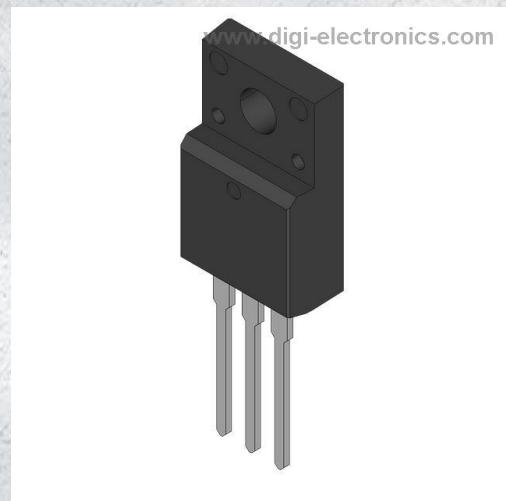


AUIRF540Z Datasheet



DiGi Electronics Part Number	AUIRF540Z-DG
Manufacturer	Infineon Technologies
Manufacturer Product Number	AUIRF540Z
Description	MOSFET N-CH 100V 36A TO220AB
Detailed Description	N-Channel 100 V 36A (T _c) 92W (T _c) Through Hole T O-220AB

<https://www.DiGi-Electronics.com>



Tel: +00 852-30501935

RFQ Email: Info@DiGi-Electronics.com

DiGi is a global authorized distributor of electronic components.

Purchase and inquiry

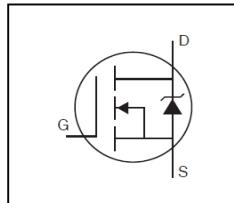
Manufacturer Product Number:		Manufacturer:	
AUIRF540Z		Infineon Technologies	
Series:		Product Status:	
HEXFET®		Active	
FET Type:		Technology:	
N-Channel		MOSFET (Metal Oxide)	
Drain to Source Voltage (Vdss):		Current - Continuous Drain (Id) @ 25°C:	
100 V		36A (Tc)	
Drive Voltage (Max Rds On, Min Rds On):		Rds On (Max) @ Id, Vgs:	
10V		26.5mOhm @ 22A, 10V	
Vgs(th) (Max) @ Id:		Gate Charge (Qg) (Max) @ Vgs:	
4V @ 250µA		63 nC @ 10 V	
Vgs (Max):		Input Capacitance (Ciss) (Max) @ Vds:	
±20V		1770 pF @ 25 V	
FET Feature:		Power Dissipation (Max):	
-		92W (Tc)	
Operating Temperature:		Mounting Type:	
-55°C ~ 175°C (Tj)		Through Hole	
Supplier Device Package:		Package / Case:	
TO-220AB		TO-220-3	
Base Product Number:			
AUIRF540			

Environmental & Export classification

RoHS Status:	Moisture Sensitivity Level (MSL):
ROHS3 Compliant	1 (Unlimited)
REACH Status:	ECCN:
REACH Unaffected	EAR99
HTSUS:	
8541.29.0095	

Features

- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified *

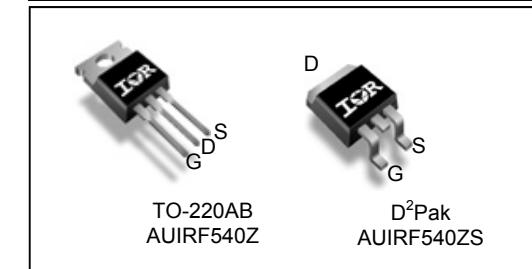


HEXFET® Power MOSFET

V_{DSS}	100V
R_{DS(on)} typ.	21mΩ
	26.5mΩ
I_D	36A

Description

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and wide variety of other applications.



G	D	S
Gate	Drain	Source

Base part number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
AUIRF540Z	TO-220	Tube	50	AUIRF540Z
AUIRF540ZS	D²-Pak	Tube	50	AUIRF540ZS
		Tape and Reel Left	800	AUIRF540ZSTR

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	36	A
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	25	
I _{DM}	Pulsed Drain Current ①	140	W
P _D @ T _C = 25°C	Maximum Power Dissipation	92	
	Linear Derating Factor	0.61	W/°C
V _{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	83	mJ
E _{AS} (tested)	Single Pulse Avalanche Energy Tested Value ⑥	120	
I _{AR}	Avalanche Current ①	See Fig.15,16, 12a, 12b	A
E _{AR}	Repetitive Avalanche Energy ①		mJ
T _J	Operating Junction and	-55 to + 175	°C
T _{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting torque, 6-32 or M3 screw ⑦	10 lbf·in (1.1N·m)	

Thermal Resistance

Symbol	Parameter	Typ.	Max.	Units
R _{θJC}	Junction-to-Case	—	1.64	°C/W
R _{θCS}	Case-to-Sink, Flat, Greased Surface ⑦	0.50	—	
R _{θJA}	Junction-to-Ambient ⑦	—	62	
R _{θJA}	Junction-to-Ambient (PCB Mount, steady state) ⑧	—	40	

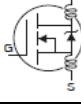
HEXFET® is a registered trademark of Infineon.

*Qualification standards can be found at www.infineon.com

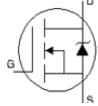
Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	100	—	—	V	$V_{GS} = 0V, I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.093	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{DS(\text{on})}$	Static Drain-to-Source On-Resistance	—	21	26.5	$\text{m}\Omega$	$V_{GS} = 10\text{V}, I_D = 22\text{A}$ ③
$V_{GS(\text{th})}$	Gate Threshold Voltage	2.0	—	4.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
g_{fs}	Forward Trans conductance	36	—	—	S	$V_{DS} = 25\text{V}, I_D = 22\text{A}$
I_{DSS}	Drain-to-Source Leakage Current	—	—	20	μA	$V_{DS} = 100\text{V}, V_{GS} = 0\text{V}$
		—	—	250		$V_{DS} = 100\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	200	nA	$V_{GS} = 20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	-200		$V_{GS} = -20\text{V}$

Dynamic Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

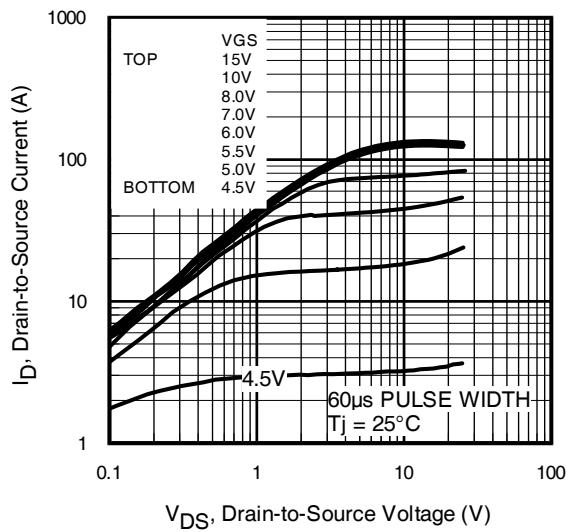
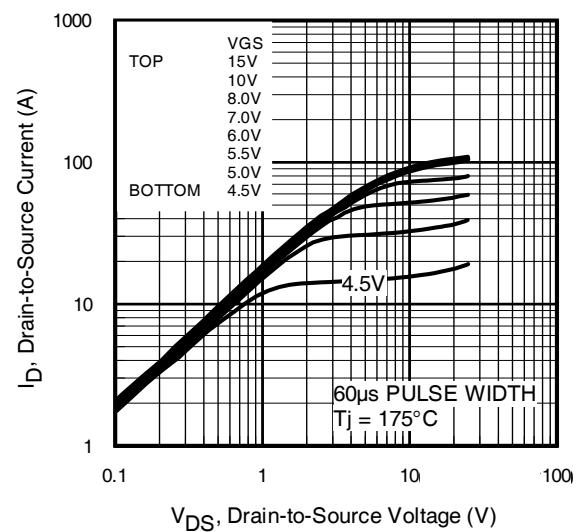
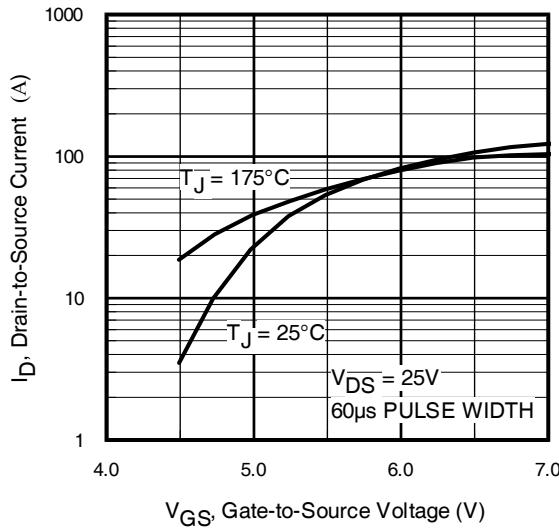
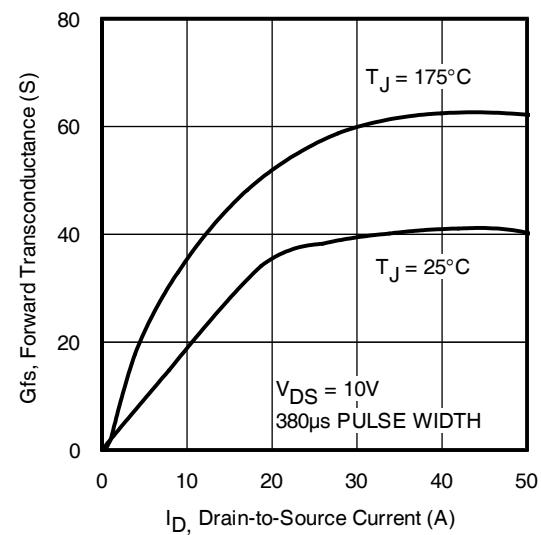
Q_g	Total Gate Charge	—	42	63	nC	$I_D = 22\text{A}$ $V_{DS} = 80\text{V}$ $V_{GS} = 10\text{V}$ ③
Q_{gs}	Gate-to-Source Charge	—	9.7	—		
Q_{gd}	Gate-to-Drain Charge	—	15	—		
$t_{d(on)}$	Turn-On Delay Time	—	15	—		$V_{DD} = 50\text{V}$
t_r	Rise Time	—	51	—		$I_D = 22\text{A}$
$t_{d(off)}$	Turn-Off Delay Time	—	43	—		$R_G = 12\Omega$
t_f	Fall Time	—	39	—		$V_{GS} = 10\text{V}$ ③
L_D	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
L_S	Internal Source Inductance	—	7.5	—		
C_{iss}	Input Capacitance	—	1770	—	pF	$V_{GS} = 0\text{V}$
C_{oss}	Output Capacitance	—	180	—		$V_{DS} = 25\text{V}$
C_{rss}	Reverse Transfer Capacitance	—	100	—		$f = 1.0\text{MHz}$, See Fig. 5
C_{oss}	Output Capacitance	—	730	—		$V_{GS} = 0\text{V}, V_{DS} = 1.0\text{V}$ $f = 1.0\text{MHz}$
C_{oss}	Output Capacitance	—	110	—		$V_{GS} = 0\text{V}, V_{DS} = 80\text{V}$ $f = 1.0\text{MHz}$
$C_{oss\ eff.}$	Effective Output Capacitance	—	170	—		$V_{GS} = 0\text{V}, V_{DS} = 0\text{V to } 80\text{V}$ ④

Diode Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_s	Continuous Source Current (Body Diode)	—	—	36	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I_{sM}	Pulsed Source Current (Body Diode) ①	—	—	140		
V_{SD}	Diode Forward Voltage	—	—	1.3		$T_J = 25^\circ\text{C}, I_s = 22\text{A}, V_{GS} = 0\text{V}$ ③
t_{rr}	Reverse Recovery Time	—	33	50		$T_J = 25^\circ\text{C}, I_F = 22\text{A}, V_{DD} = 50\text{V}$
Q_{rr}	Reverse Recovery Charge	—	41	62		$dI/dt = 100\text{A}/\mu\text{s}$ ③
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S + L_D$)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Limited by $T_{J\max}$, starting $T_J = 25^\circ\text{C}$, $L = 0.46\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 20\text{A}$, $V_{GS} = 10\text{V}$. Part not recommended for use above this value.
- ③ Pulse width $\leq 1.0\text{ms}$; duty cycle $\leq 2\%$.
- ④ $C_{oss\ eff.}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- ⑤ Limited by $T_{J\max}$, see Fig. 12a, 12b, 15, 16 for typical repetitive avalanche performance.
- ⑥ This value determined from sample failure population, $T_J = 25^\circ\text{C}$, $L = 0.46\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 20\text{A}$, $V_{GS} = 10\text{V}$.
- ⑦ This is only applied to TO-220AB package.
- ⑧ This is applied to D²Pak When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994


Fig. 1 Typical Output Characteristics

Fig. 2 Typical Output Characteristics

Fig. 3 Typical Transfer Characteristics

Fig. 4 Typical Forward Transconductance vs. Drain Current

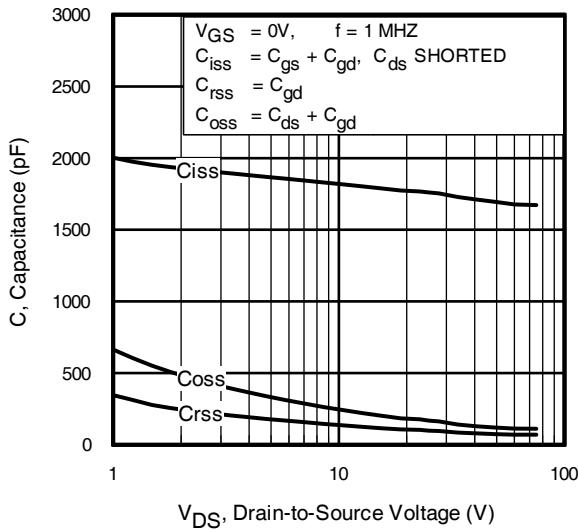


Fig 5. Typical Capacitance vs.
Drain-to-Source Voltage

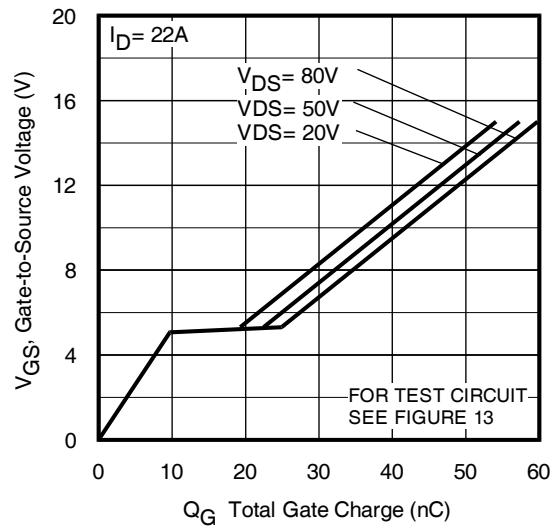


Fig 6. Typical Gate Charge vs.
Gate-to-Source Voltage

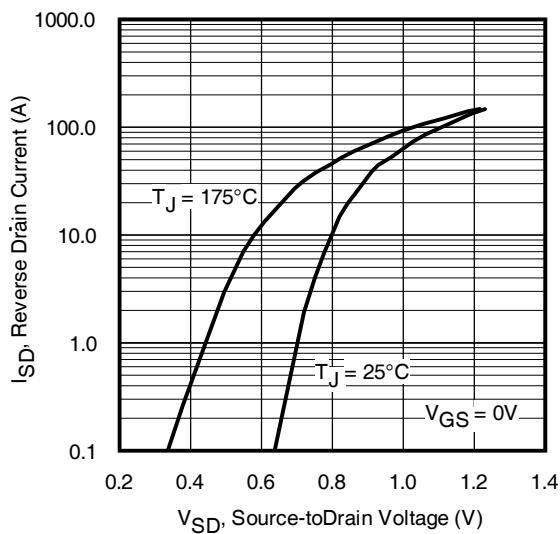


Fig. 7 Typical Source-to-Drain Diode
Forward Voltage

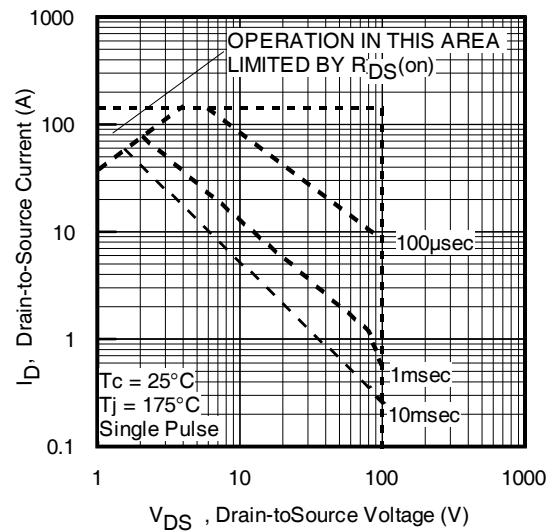


Fig 8. Maximum Safe Operating Area

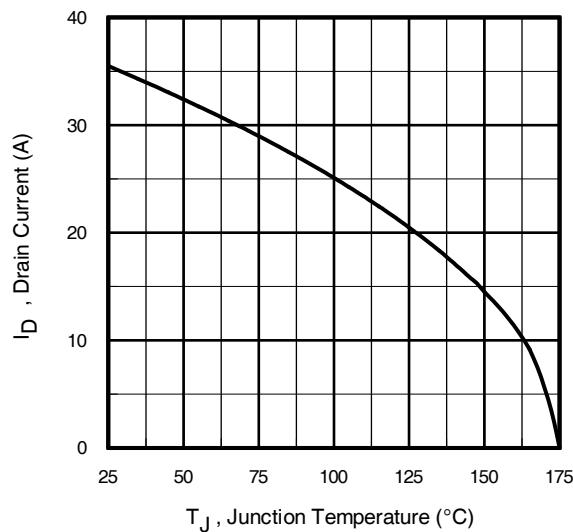


Fig 9. Maximum Drain Current vs. Case Temperature

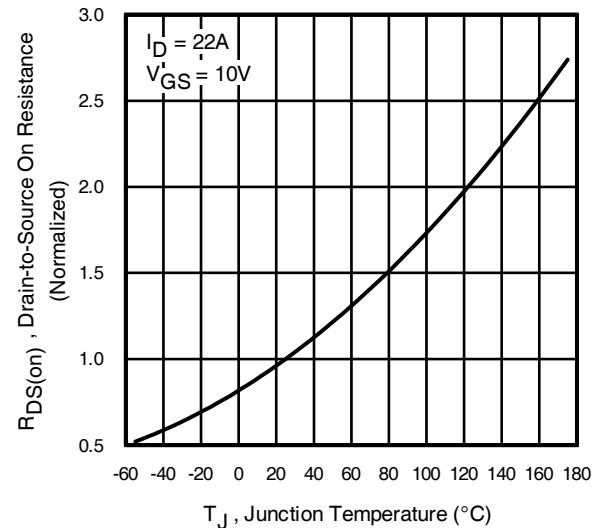


Fig 10. Normalized On-Resistance vs. Temperature

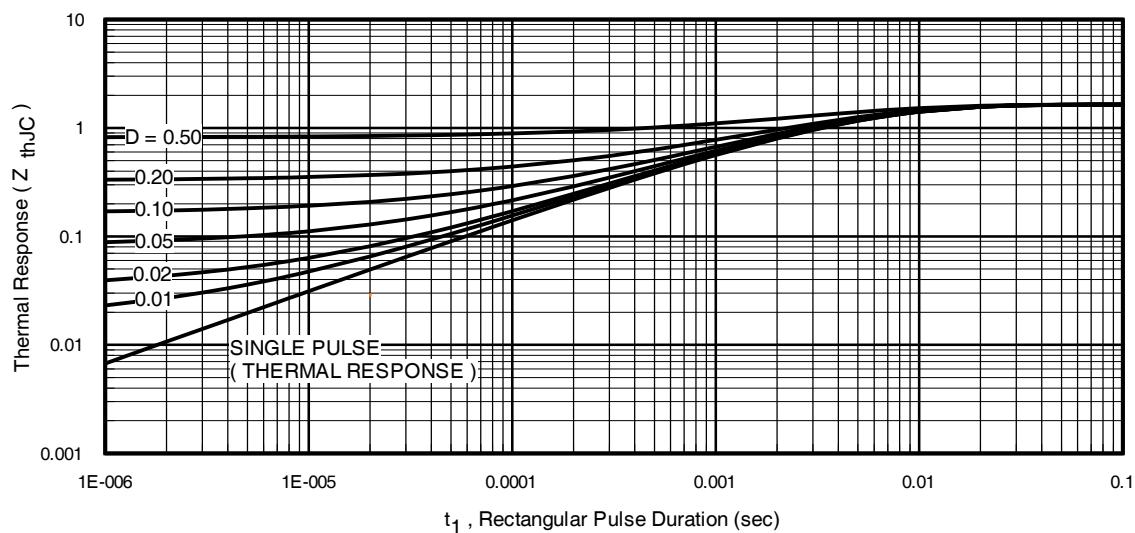


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

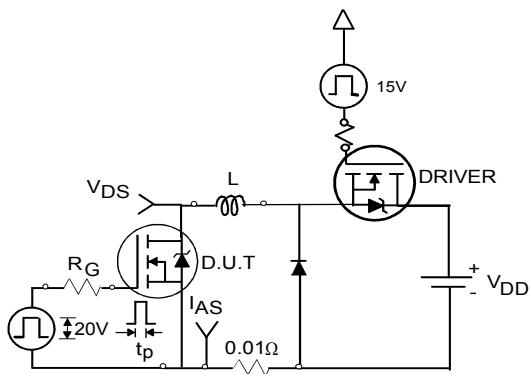


Fig 12a. Unclamped Inductive Test Circuit

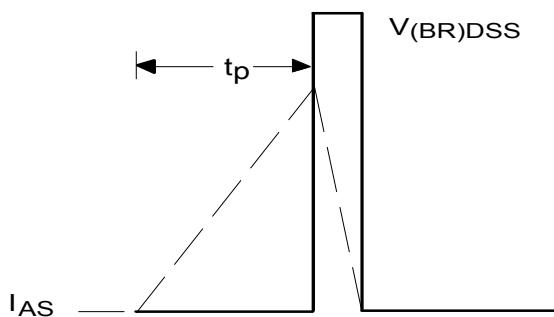


Fig 12b. Unclamped Inductive Waveforms

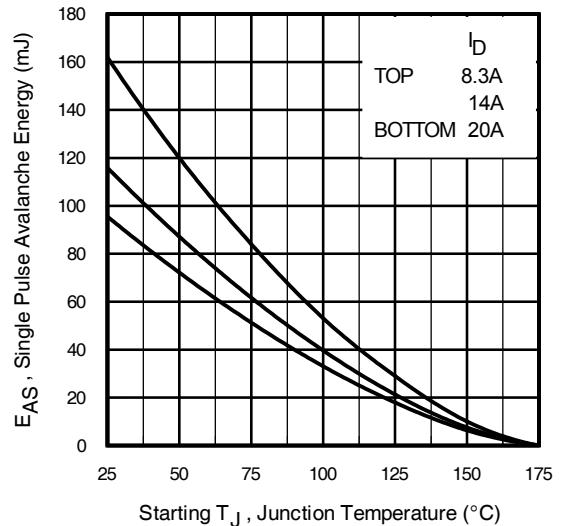


Fig 12c. Maximum Avalanche Energy vs. Drain Current

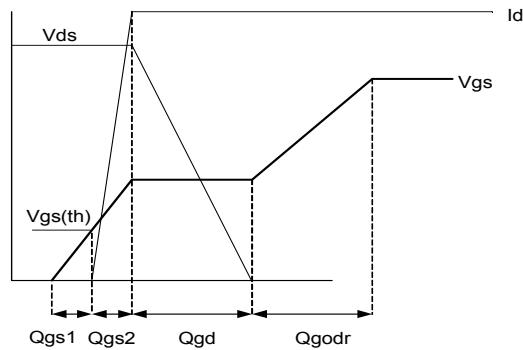


Fig 13a. Gate Charge Waveform

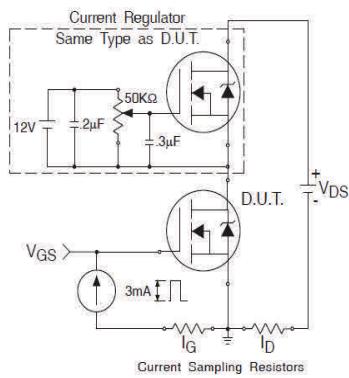


Fig 13b. Gate Charge Test Circuit

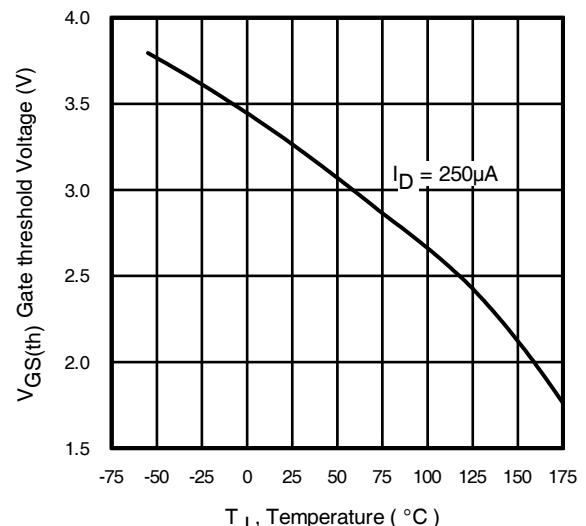


Fig 14. Threshold Voltage vs. Temperature

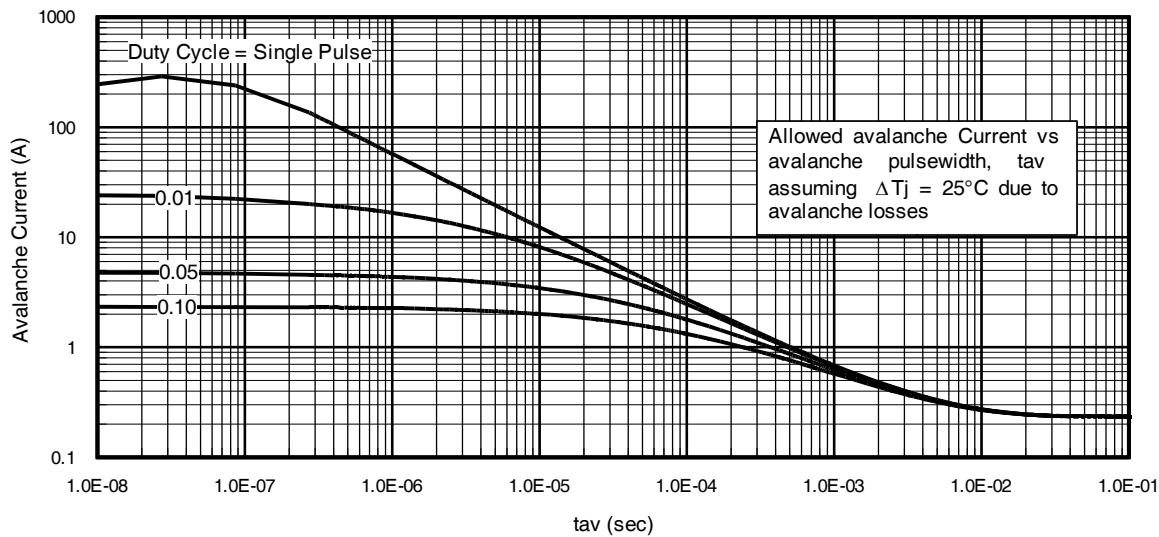


Fig 15. Typical Avalanche Current vs. Pulse width

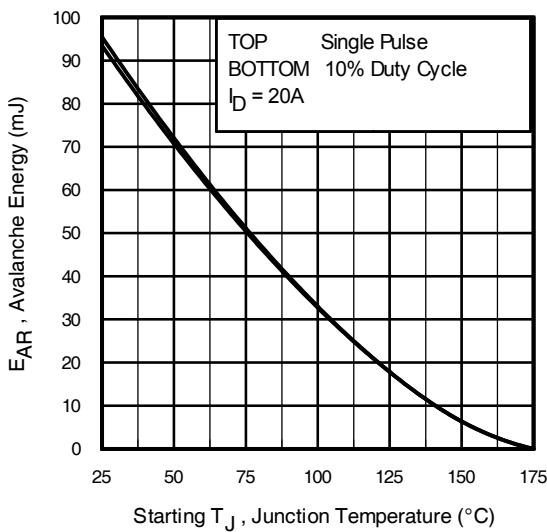


Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 15, 16:
(For further info, see AN-1005 at www.infineon.com)

1. Avalanche failures assumption:
Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
 2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
 4. $P_{D(ave)}$ = Average power dissipation per single avalanche pulse.
 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
 6. I_{av} = Allowable avalanche current.
 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).
- t_{av} = Average time in avalanche.
 D = Duty cycle in avalanche = $t_{av} \cdot f$
 $Z_{thJC}(D, t_{av})$ = Transient thermal resistance, see Figures 13)

$$P_{D(ave)} = 1/2 (1.3 \cdot BV \cdot I_{av}) = \Delta T / Z_{thJC}$$

$$I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$$

$$E_{AS(AR)} = P_{D(ave)} \cdot t_{av}$$

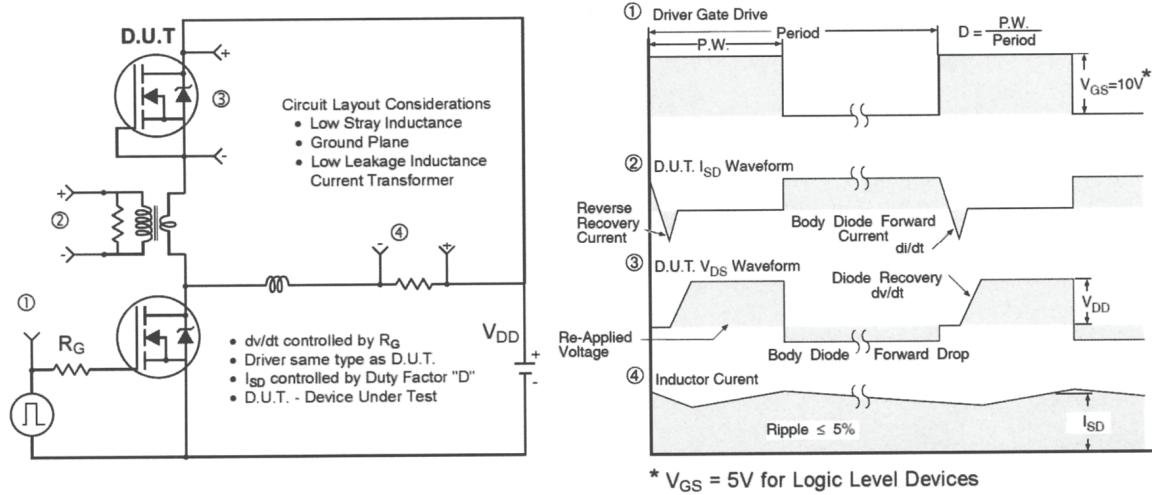


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

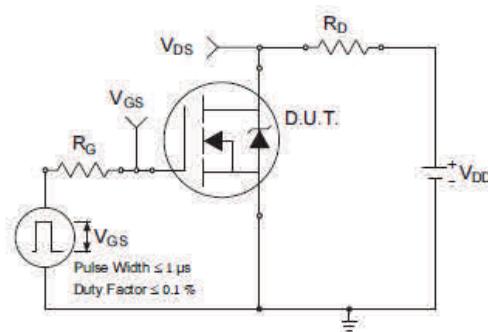


Fig 18a. Switching Time Test Circuit

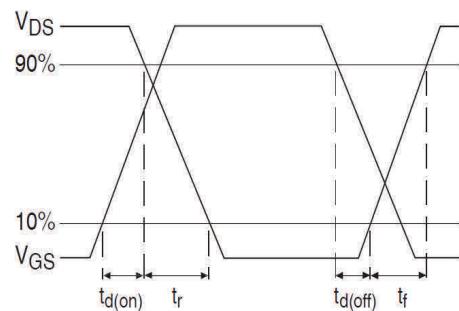
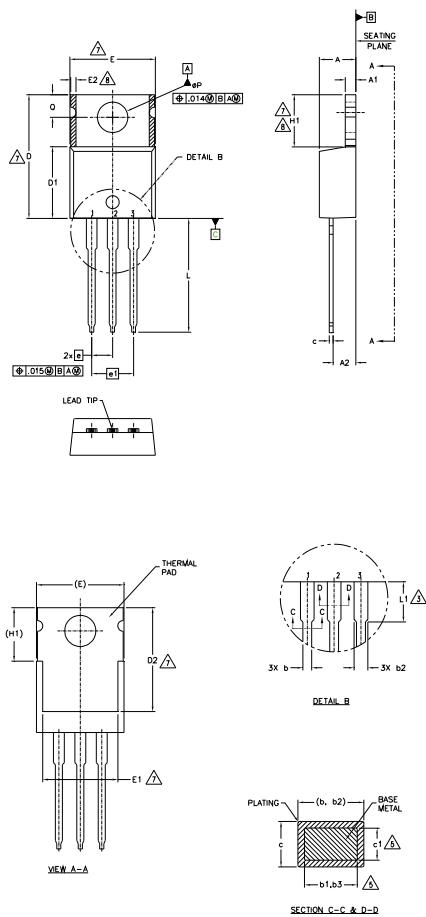


Fig 18b. Switching Time Waveforms

TO-220AB Package Outline (Dimensions are shown in millimeters (inches))



NOTES

- 
 - 1.- DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M- 1994.
 - 2.- DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].
 - 3.- LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.
 - 4.- DIMENSION D, D1 & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED ".005" (.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
 - 5.- DIMENSION b1, b3 & c1 APPLY TO BASE METAL ONLY.
 - 6.- CONTROLLING DIMENSION : INCHES.
 - 7.- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
 - 8.- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.
 - 9.- OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.), WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

SYMBOL	DIMENSIONS				NOTES	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	3.56	4.83	.140	.190		
A1	1.14	1.40	.045	.055		
A2	2.03	2.92	.080	.115		
b	0.38	1.01	.015	.040		
b1	0.38	0.97	.015	.038	5	
b2	1.14	1.78	.045	.070		
b3	1.14	1.73	.045	.068	5	
c	0.36	0.61	.014	.024		
c1	0.36	0.56	.014	.022	5	
D	14.22	16.51	.560	.650	4	
D1	8.38	9.02	.330	.355		
D2	11.68	12.88	.460	.507	7	
E	9.65	10.67	.380	.420	4,7	
E1	6.86	8.89	.270	.350	7	
E2	-	0.76	-	.030	8	
e	2.54	BSC	.100	BSC		
e1	5.08	BSC	.200	BSC		
H1	5.84	6.86	.230	.270	7,8	
L	12.70	14.73	.500	.580		
L1	3.56	4.06	.140	.160		
ØP	3.54	4.08	.139	.161	3	
Q	2.54	3.42	.100	.135		

LEAD ASSIGNMENTS

HEXFET

- ..- GATE
.- DRAIN
. SOURCE

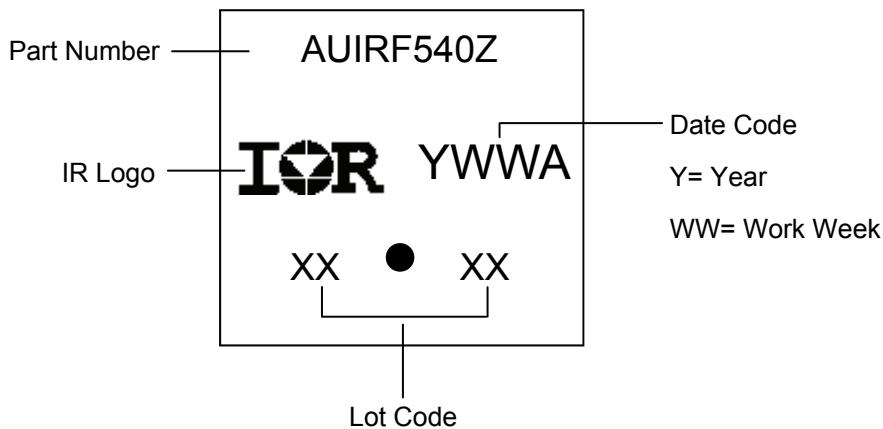
IGBTs, CoPACK

- 1.- GATE
 - 2.- COLLECTOR
 - 3.- Emitter

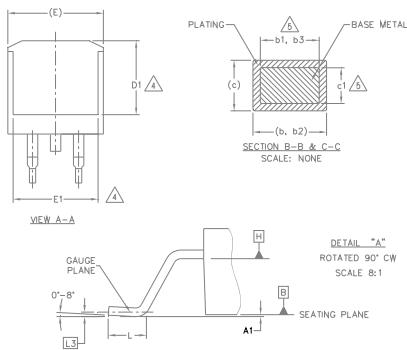
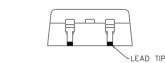
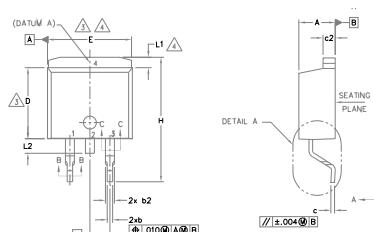
WODES

- 1.- ANODE
 - 2.- CATHODE
 - 3.- ANODE

TO-220AB Part Marking Information



TO-220AB package is not recommended for Surface Mount Application.

D²Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))


SYMBOL	DIMENSIONS				NOTES	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	4.06	4.83	.160	.190		
A1	0.00	0.254	.000	.010		
b	0.51	0.99	.020	.039		
b1	0.51	0.89	.020	.035	5	
b2	1.14	1.78	.045	.070		
b3	1.14	1.73	.045	.068	5	
c	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023	5	
c2	1.14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	—	.270	—	4	
E	9.65	10.67	.380	.420	3,4	
E1	6.22	—	.245	—	4	
e	2.54	BSC	.100	BSC		
H	14.61	15.88	.575	.625		
L	1.78	2.79	.070	.110		
L1	—	1.68	—	.066	4	
L2	—	1.78	—	.070		
L3	0.25	BSC	.010	BSC		

LEAD ASSIGNMENTS
DIODES

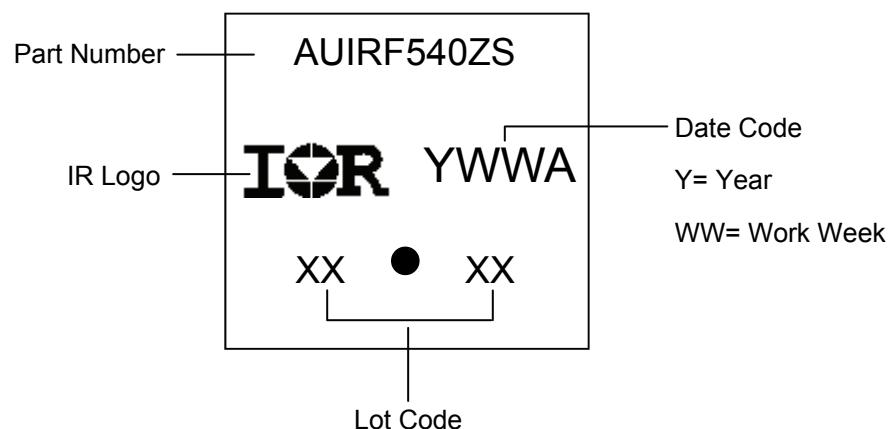
- 1.- ANODE (TWO DIE) / OPEN (ONE DIE)
- 2, 4.- CATHODE
- 3.- ANODE

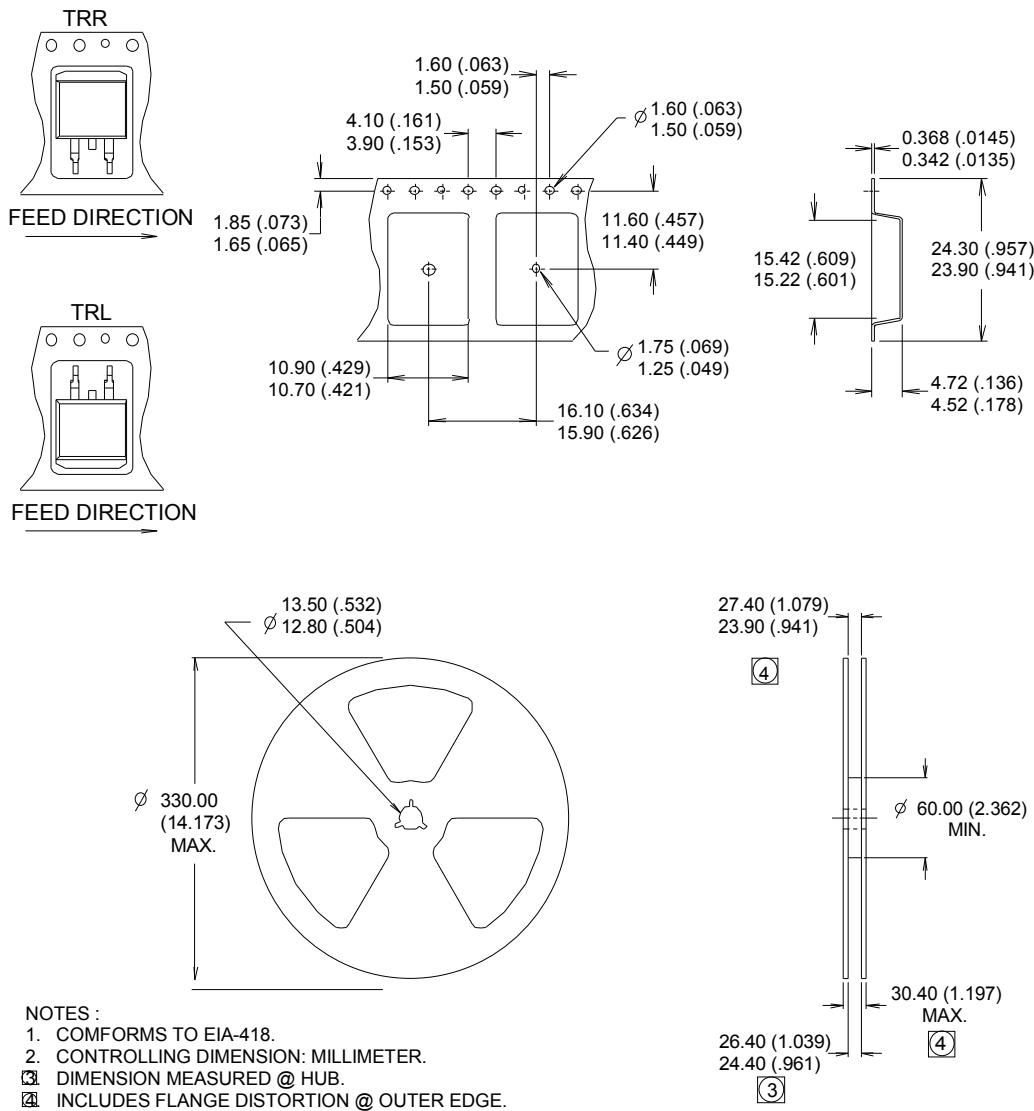
HEXFET

- 1.- GATE
- 2, 4.- DRAIN
- 3.- SOURCE

IGBTs, CoPACK

- 1.- GATE
- 2, 4.- COLLECTOR
- 3.- Emitter

D²Pak (TO-263AB) Part Marking Information


D²Pak (TO-263AB) Tape & Reel Information (Dimensions are shown in millimeters (inches))

Qualification Information

Qualification Level		Automotive (per AEC-Q101)	
Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.			
Moisture Sensitivity Level	TO-220AB	N/A	
	D ² -Pak	MSL1	
ESD	Machine Model	Class M4 (400V) [†] AEC-Q101-002	
	Human Body Model	Class H1B (1000V) [†] AEC-Q101-001	
	Charged Device Model	Class C3 (750V) [†] AEC-Q101-005	
RoHS Compliant		Yes	

[†] Highest passing voltage.

Revision History

Date	Comments
9/30/2015	<ul style="list-style-type: none"> • Updated datasheet with corporate template • Corrected ordering table on page 1.
09/22/2017	<ul style="list-style-type: none"> • Corrected typo error on part marking on pages 9,10.

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WARNINGS

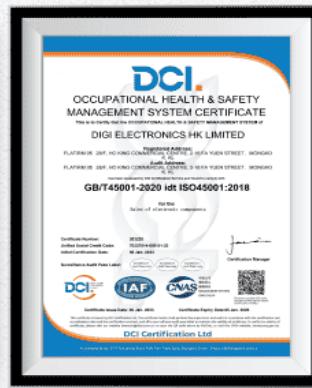
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